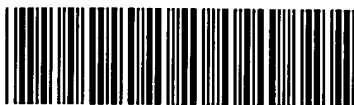


Search Notes

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10/533,267

Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

HAGIWARA ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR